

RoHS Compliant Product  
 A suffix of "-C" specifies halogen and lead-free

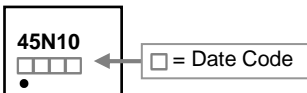
**DESCRIPTION**

The SSP45N10 is the highest performance trench N-ch MOSFETs with extreme high cell density , which provide excellent R<sub>DS(ON)</sub> and gate charge for most of the synchronous buck converter applications .The SSP45N10 meet the RoHS and Green Product requirement , 100% EAS guaranteed with full function reliability approved.

**FEATURES**

- Simple Drive Requirement
- Small Package Outline

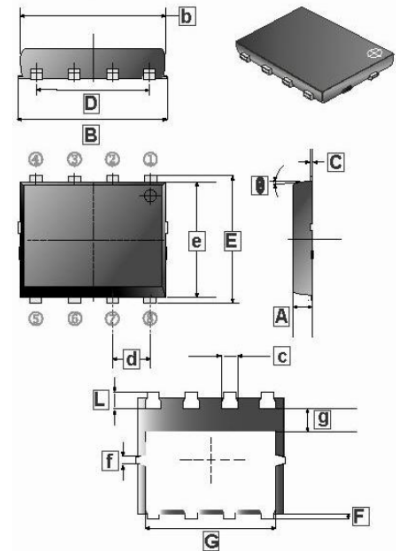
**MARKING**



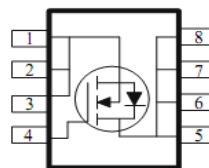
**PACKAGE INFORMATION**

Package	MPQ	Leader Size
SOP-8PP	3K	13 inch

**SOP-8PP**



**TOP VIEW**



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	0.80	1.00	θ	0°	10°
B	5.3 BCS.		b	5.2 BCS	
C	0.15	0.25	c	0.20	0.50
D	3.8 BCS.		d	1.27BCS.	
E	6.05 BCS.		e	5.65 BCS.	
F	0.03	0.30	f	0.10	0.40
G	4.35 BCS.		g	1.3 BCS.	
L	0.40	0.70			

**ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub>=25°C unless otherwise specified)**

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V <sub>DS</sub>	100	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Continuous Drain Current <sup>1</sup> , V <sub>GS</sub> @10V	I <sub>D</sub>	T <sub>C</sub> =25°C	45
		T <sub>C</sub> =100°C	28
Pulsed Drain Current <sup>2</sup>	I <sub>DM</sub>	100	A
Power Dissipation <sup>4</sup>	P <sub>D</sub>	90	W
Single Pulse Avalanche Energy <sup>3</sup>	E <sub>AS</sub>	98	mJ
Single Pulse Avalanche Current	I <sub>AS</sub>	41	A
Operating Junction and Storage Temperature Range	T <sub>j</sub> , T <sub>stg</sub>	-55~150	°C
<b>Thermal Resistance Rating</b>			
Maximum Junction to Case <sup>1</sup>	R <sub>θJC</sub>	1.4	°C / W
Maximum Junction to Ambient <sup>1</sup>	R <sub>θJA</sub>	36	°C / W

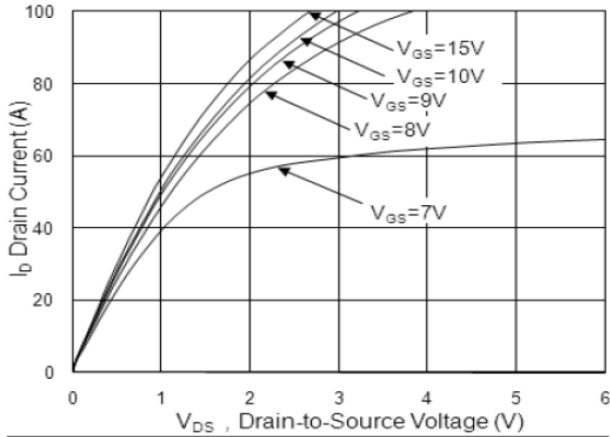
**ELECTRICAL CHARACTERISTICS** ( $T_A=25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions	
<b>Static</b>							
Drain-Source Breakdown Voltage	$BV_{DSS}$	100	-	-	V	$V_{GS}=0, I_D=250\mu\text{A}$	
Gate-Threshold Voltage	$V_{GS(th)}$	2.5	-	4.5	V	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	
Forward Transconductance	$g_{fs}$	-	27	-	S	$V_{DS}=5\text{V}, I_D=30\text{A}$	
Gate Resistance	$R_G$	-	1.9	3.8	$\Omega$	$f=1\text{MHz}$	
Gate-Body Leakage Current	$I_{GSS}$	-	-	$\pm 100$	nA	$V_{GS}=\pm 20\text{V}$	
Drain-Source Leakage Current	$T_J=25^\circ\text{C}$	$I_{DSS}$	-	-	1	$\mu\text{A}$	$V_{DS}=80\text{V}, V_{GS}=0$
	$T_J=55^\circ\text{C}$		-	-	5		$V_{DS}=80\text{V}, V_{GS}=0$
Drain-Source On-Resistance <sup>2</sup>	$R_{DS(ON)}$	-	19	22	m $\Omega$	$V_{GS}=10\text{V}, I_D=30\text{A}$	
		-	25	30		$V_{GS}=7\text{V}, I_D=15\text{A}$	
<b>Dynamic</b>							
Total Gate Charge	$Q_g$	-	27.6	-	nC	$V_{DS}=80\text{V}, V_{GS}=10\text{V}, I_D=30\text{A}$	
Gate-Source Charge	$Q_{gs}$	-	11.4	-			
Gate-Drain ("Miller") Charge	$Q_{gd}$	-	7.9	-			
Turn-on Delay Time <sup>2</sup>	$T_{d(on)}$	-	15.6	-	nS	$V_{DD}=50\text{V}, V_{GS}=10\text{V}, R_G=3.3\Omega, I_D=30\text{A}$	
Rise Time	$T_r$	-	17.2	-			
Turn-off Delay Time	$T_{d(off)}$	-	16.8	-			
Fall Time	$T_f$	-	9.2	-			
Input Capacitance	$C_{iss}$	-	1890	-	pF	$V_{GS}=0, V_{DS}=15\text{V}, f=1.0\text{MHz}$	
Output Capacitance	$C_{oss}$	-	268	-			
Reverse Transfer Capacitance	$C_{rss}$	-	67	-			
<b>Guaranteed Avalanche Characteristics</b>							
Single Pulse Avalanche Energy <sup>5</sup>	EAS	53	-	-	mJ	$V_{DD}=50\text{V}, L=0.1\text{mH}, I_{AS}=30\text{A}$	
<b>Source-Drain Diode</b>							
Diode Forward Voltage <sup>2</sup>	$V_{SD}$	-	-	1	V	$I_S=1\text{A}, V_{GS}=0$	
Continuous Source Current <sup>1,6</sup>	$I_S$	-	-	45	A	$V_D=V_G=0, \text{Force Current}$	
Pulsed Source Current <sup>2,6</sup>	$I_{SM}$	-	-	100	A		
Reverse Recovery Time	$T_{RR}$	-	34	-	ns	$I_F=30\text{A}, T_J=25^\circ\text{C}$	
Reverse Recovery Charge	$Q_{RR}$	-	47	-	nC	$di/dt=100\text{A}/\mu\text{s}$	

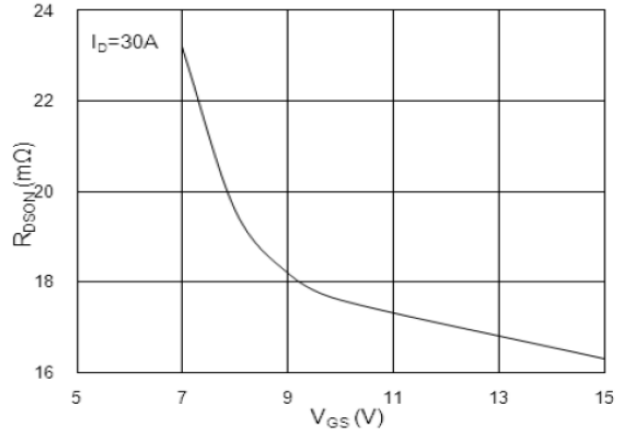
Notes:

- The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper ,  $\leq 10\text{sec}$  ,  $125^\circ\text{C}/\text{W}$  at steady state
- The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$
- The EAS data shows Max. rating . The test condition is  $V_{DD}=25\text{V}, V_{GS}=10\text{V}, L=0.1\text{mH}, I_{AS}=53.8\text{A}$
- The power dissipation is limited by  $150^\circ\text{C}$  junction temperature
- The Min. value is 100% EAS tested guarantee.
- The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation

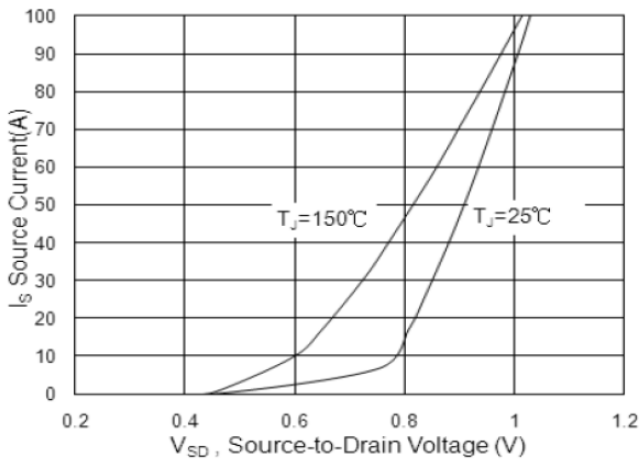
**CHARACTERISTIC CURVES**



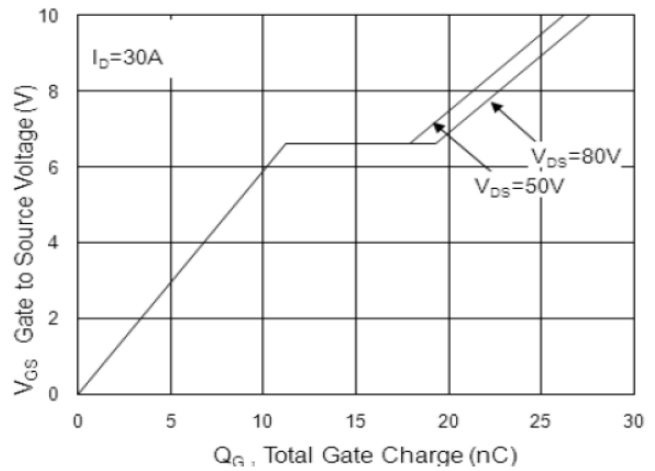
**Fig.1 Typical Output Characteristics**



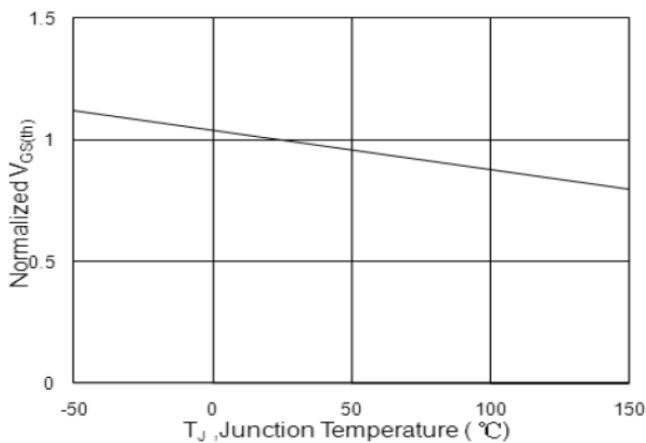
**Fig.2 On-Resistance v.s Gate-Source**



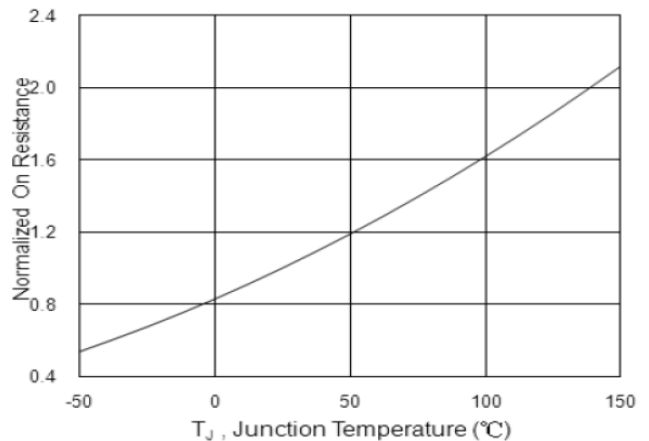
**Fig.3 Forward Characteristics of Reverse**



**Fig.4 Gate-Charge Characteristics**

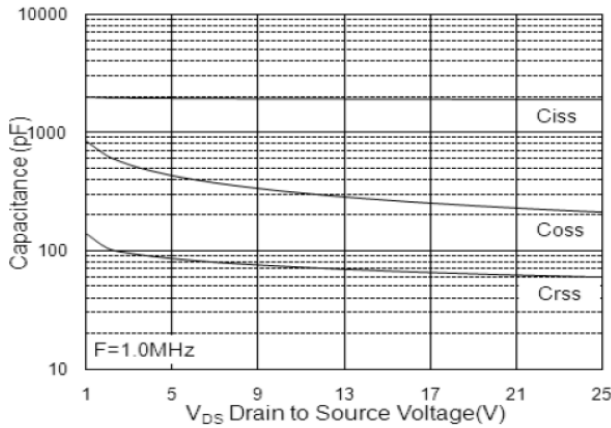


**Fig.5 Normalized  $V_{GS(th)}$  v.s  $T_J$**

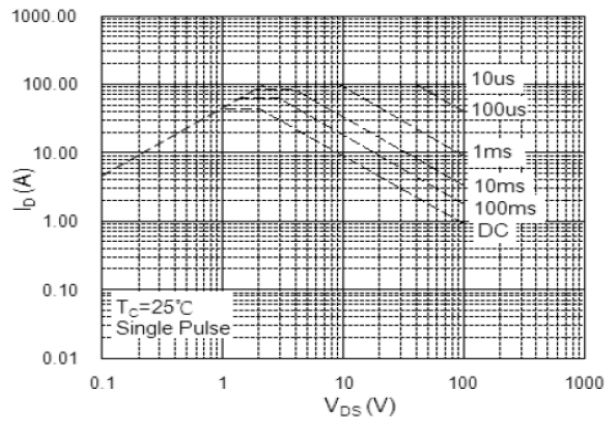


**Fig.6 Normalized  $R_{DS(ON)}$  v.s  $T_J$**

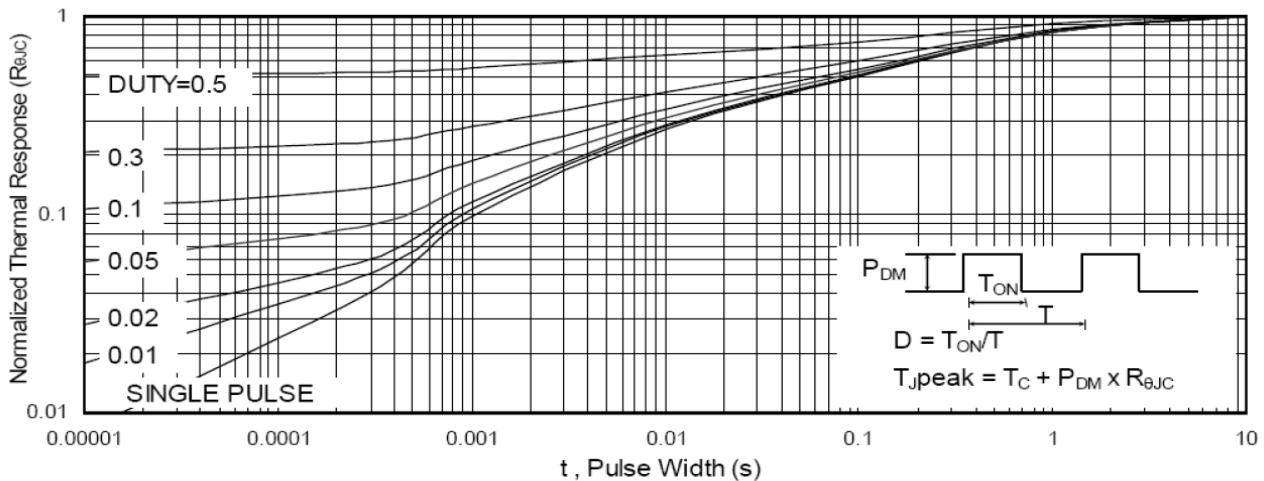
**CHARACTERISTIC CURVES**



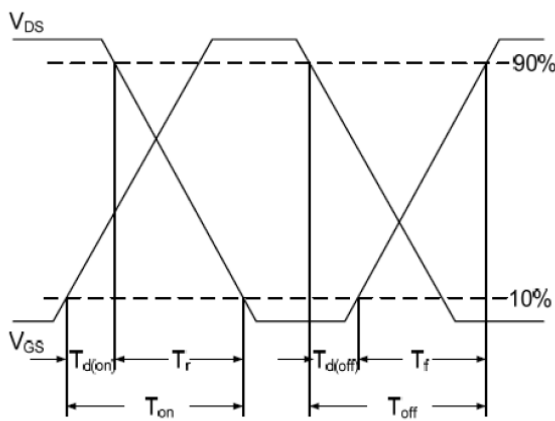
**Fig.7 Capacitance**



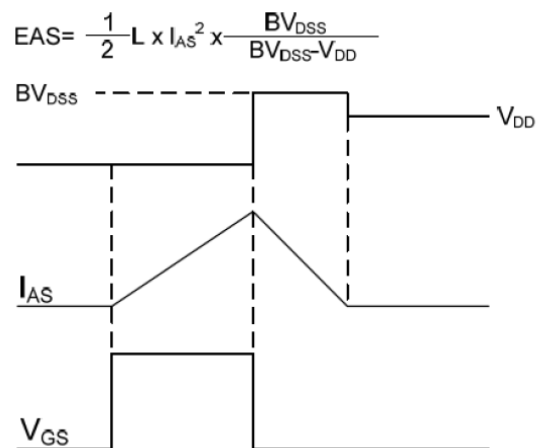
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**



**Fig.10 Switching Time Waveform**



**Fig.11 Unclamped Inductive Switching Waveform**